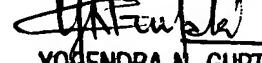


Issue Classification				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/786,017		BABIN ET AL.	
Examiner				Art Unit			
Maria Veronica D. Ewald		1722					

ORIGINAL				CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
425	572	425	588				
INTERNATIONAL CLASSIFICATION		264	328.8	328.12			
B	2	9	C	45/00			
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Maria Veronica Ewald  (Assistant Examiner)				YOGENDRA N. GUPTA  SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 1700 (Primary Examiner)			
8/21/07 (Date)				8/28/07 (Date)			